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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	168MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	51
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	192K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f415rgt6tr

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

2.2.5 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code from a 32-bit data word and a fixed generator polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a software signature during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

2.2.6 Embedded SRAM

All STM32F41xxx products embed:

Up to 192 Kbytes of system SRAM including 64 Kbytes of CCM (core coupled memory) data RAM

RAM memory is accessed (read/write) at CPU clock speed with 0 wait states.

• 4 Kbytes of backup SRAM

This area is accessible only from the CPU. Its content is protected against possible unwanted write accesses, and is retained in Standby or VBAT mode.

2.2.7 Multi-AHB bus matrix

The 32-bit multi-AHB bus matrix interconnects all the masters (CPU, DMAs, Ethernet, USB HS) and the slaves (Flash memory, RAM, FSMC, AHB and APB peripherals) and ensures a seamless and efficient operation even when several high-speed peripherals work simultaneously.





Figure 7. Power supply supervisor interconnection with internal reset OFF

1. PDR = 1.7 V for reduce temperature range; PDR = 1.8 V for all temperature range.

The V_{DD} specified threshold, below which the device must be maintained under reset, is 1.8 V (see *Figure 7*). This supply voltage can drop to 1.7 V when the device operates in the 0 to 70 °C temperature range.

A comprehensive set of power-saving mode allows to design low-power applications.

When the internal reset is OFF, the following integrated features are no more supported:

- The integrated power-on reset (POR) / power-down reset (PDR) circuitry is disabled
- The brownout reset (BOR) circuitry is disabled
- The embedded programmable voltage detector (PVD) is disabled
- V_{BAT} functionality is no more available and V_{BAT} pin should be connected to V_{DD}

All packages, except for the LQFP64 and LQFP100, allow to disable the internal reset through the PDR_ON signal.



2.2.40 Embedded Trace Macrocell™

The ARM Embedded Trace Macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F41xxx through a small number of ETM pins to an external hardware trace port analyser (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer that runs the debugger software. TPA hardware is commercially available from common development tool vendors.

The Embedded Trace Macrocell operates with third party debugger software tools.



	I	Pin r	numb	er			•			, , , , , , , , , , , , , , , , , , ,	
LQFP64	WLCSP90	LQFP100	LQFP144	UFBGA176	LQFP176	Pin name (function after reset) ⁽¹⁾	Pin type	I / O structure	Notes	Alternate functions	Additional functions
-	A4	85	118	D10	146	PD4	I/O	FT	-	FSMC_NOE/ USART2_RTS/ EVENTOUT	-
-	C6	86	119	C11	147	PD5	I/O	FT	-	FSMC_NWE/USART2_TX/ EVENTOUT	-
-	-	-	120	D8	148	V _{SS}	S	-	-	-	_
-	-	-	121	C8	149	V _{DD}	S	-	-	-	-
-	B5	87	122	B11	150	PD6	I/O	FT	-	FSMC_NWAIT/ USART2_RX/ EVENTOUT	-
-	A5	88	123	A11	151	PD7	I/O	FT	-	USART2_CK/FSMC_NE1/ FSMC_NCE2/ EVENTOUT	-
-	-	-	124	C10	152	PG9	I/O	FT	-	USART6_RX / FSMC_NE2/FSMC_NCE3/ EVENTOUT	-
-	-	-	125	B10	153	PG10	I/O	FT	-	FSMC_NCE4_1/ FSMC_NE3/ EVENTOUT	-
-	-	-	126	В9	154	PG11	I/O	FT	-	FSMC_NCE4_2 / ETH_MII_TX_EN/ ETH_RMII_TX_EN/ EVENTOUT	-
-	-	-	127	B8	155	PG12	I/O	FT	-	FSMC_NE4 / USART6_RTS/ EVENTOUT	-
-	-	-	128	A8	156	PG13	I/O	FT	-	FSMC_A24 / USART6_CTS /ETH_MII_TXD0/ ETH_RMII_TXD0/ EVENTOUT	-
-	-	-	129	A7	157	PG14	I/O	FT	-	FSMC_A25 / USART6_TX /ETH_MII_TXD1/ ETH_RMII_TXD1/ EVENTOUT	-
-	E8	-	130	D7	158	V _{SS}	S	-	-	-	-
-	F7	-	131	C7	159	V _{DD}	S	-	-	-	_
-	-	-	132	B7	160	PG15	I/O	FT	-	USART6_CTS / DCMI_D13/ EVENTOUT	-

Table 7. STM32F41xxx pin and ball definitions (continued)



							Table	9. Alterr	nate funct	tion ma	pping						
		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13		
P	ort	SYS	TIM1/2	TIM3/4/5	TIM8/9/10 /11	I2C1/2/3	SPI1/SPI2/ I2S2/I2S2e xt	SPI3/I2Sext /I2S3	USART1/2/3/ I2S3ext	UART4/5/ USART6	CAN1/2 TIM12/13/ 14	OTG_FS/ OTG_HS	ЕТН	FSMC/SDIO /OTG_FS	DCMI	AF14	AF15
	PA0	-	TIM2_CH1_ ETR	TIM 5_CH1	TIM8_ETR	-	-	-	USART2_CTS	UART4_TX	-	-	ETH_MII_CRS	-	-	-	EVENTOUT
	PA1	-	TIM2_CH2	TIM5_CH2	-	-	-	-	USART2_RTS	UART4_RX	-	-	ETH_MII _RX_CLK ETH_RMIIREF _CLK	-	-	-	EVENTOUT
	PA2	-	TIM2_CH3	TIM5_CH3	TIM9_CH1	-	-	-	USART2_TX	-	-	-	ETH_MDIO	-	-	-	EVENTOUT
	PA3	-	TIM2_CH4	TIM5_CH4	TIM9_CH2	-	-	-	USART2_RX	-	-	OTG_HS_ULPI_ D0	ETH _MII_COL	-	-	-	EVENTOUT
	PA4	-	-	-	-	-	SPI1_NSS	SPI3_NSS I2S3_WS	USART2_CK	-	-	-	-	OTG_HS_SOF	DCMI_ HSYNC	-	EVENTOUT
	PA5	-	TIM2_CH1_ ETR	-	TIM8_CH1N	-	SPI1_SCK	-	-	-	-	OTG_HS_ULPI_ CK	-	-	-	-	EVENTOUT
	PA6	-	TIM1_BKIN	TIM3_CH1	TIM8_BKIN	-	SPI1_MISO	-	-	-	TIM13_CH1	-	-	-	DCMI_PIXCK	-	EVENTOUT
Port A	PA7	-	TIM1_CH1N	TIM3_CH2	TIM8_CH1N	-	SPI1_MOSI	-	-	-	TIM14_CH1	-	ETH_MII_RX_DV ETH_RMII _CRS_DV	-	-	-	EVENTOUT
	PA8	MCO1	TIM1_CH1	-	-	I2C3_SCL	-	-	USART1_CK	-	-	OTG_FS_SOF	-	-	-	-	EVENTOUT
	PA9	-	TIM1_CH2	-	-	I2C3_ SMBA	-	-	USART1_TX	-	-	-	-	-	DCMI_D0	-	EVENTOUT
	PA10	-	TIM1_CH3	-	-	-	-	-	USART1_RX	-	-	OTG_FS_ID	-	-	DCMI_D1	-	EVENTOUT
	PA11	-	TIM1_CH4	-	-	-	-	-	USART1_CTS	-	CAN1_RX	OTG_FS_DM	-	-	-	-	EVENTOUT
	PA12	-	TIM1_ETR	-	-	-	-	-	USART1_RTS	-	CAN1_TX	OTG_FS_DP	-	-	-	-	EVENTOUT
	PA13	JTMS- SWDIO	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
	PA14	JTCK- SWCLK	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
	PA15	JTDI	TIM 2_CH1 TIM 2_ETR	-	-	-	SPI1_NSS	SPI3_NSS/ I2S3_WS	-	-	-	-	-	-	-	-	EVENTOUT

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Pinouts and pin description

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		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13		
P	ort	SYS	TIM1/2	TIM3/4/5	TIM8/9/10 /11	I2C1/2/3	SPI1/SPI2/ I2S2/I2S2e xt	SPI3/I2Sext /I2S3	USART1/2/3/ I2S3ext	UART4/5/ USART6	CAN1/2 TIM12/13/ 14	OTG_FS/ OTG_HS	ЕТН	FSMC/SDIO /OTG_FS	DCMI	AF14	AF15
	PD0	-	-	-	-	-	-	-	-	-	CAN1_RX	-	-	FSMC_D2	-	-	EVENTOUT
	PD1	-	-	-	-	-	-	-	-	-	CAN1_TX	-	-	FSMC_D3	-	-	EVENTOUT
	PD2	-	-	TIM3_ETR	-	-	-	-	-	UART5_RX	-	-	-	SDIO_CMD	DCMI_D11	-	EVENTOUT
	PD3	-	-	-	-	-	-	-	USART2_CTS	-	-	-	-	FSMC_CLK	-	-	EVENTOUT
	PD4	-	-	-	-	-	-	-	USART2_RTS	-	-	-	-	FSMC_NOE	-	-	EVENTOUT
	PD5	-	-	-	-	-	-	-	USART2_TX	-	-	-	-	FSMC_NWE	-	-	EVENTOUT
	PD6	-	-	-	-	-	-	-	USART2_RX	-	-	-	-	FSMC_NWAIT	-	-	EVENTOUT
Port D	PD7	-	-	-	-	-	-	-	USART2_CK	-	-	-	-	FSMC_NE1/ FSMC_NCE2	-	-	EVENTOUT
	PD8	-	-	-	-	-	-	-	USART3_TX	-	-	-	-	FSMC_D13	-	-	EVENTOUT
	PD9	-	-	-	-	-	-	-	USART3_RX	-	-	-	-	FSMC_D14	-	-	EVENTOUT
	PD10	-	-	-	-	-	-	-	USART3_CK	-	-	-	-	FSMC_D15	-	-	EVENTOUT
	PD11	-	-	-	-	-	-	-	USART3_CTS	-	-	-	-	FSMC_A16	-	-	EVENTOUT
	PD12	-	-	TIM4_CH1	-	-	-	-	USART3_RTS	-	-	-	-	FSMC_A17	-	-	EVENTOUT
	PD13	-	-	TIM4_CH2	-	-	-	-	-	-	-	-	-	FSMC_A18	-	-	EVENTOUT
	PD14	-	-	TIM4_CH3	-	-	-	-	-	-	-	-	-	FSMC_D0	-	-	EVENTOUT
	PD15	-	-	TIM4_CH4	-	-	-	-	-	-	-	-	-	FSMC_D1	-	-	EVENTOUT

Table 9. Alternate function mapping (continued)

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Bus	Boundary address	Peripheral
	0x4000 7800 - 0x4000 7FFF	Reserved
	0x4000 7400 - 0x4000 77FF	DAC
	0x4000 7000 - 0x4000 73FF	PWR
	0x4000 6C00 - 0x4000 6FFF	Reserved
	0x4000 6800 - 0x4000 6BFF	CAN2
	0x4000 6400 - 0x4000 67FF	CAN1
	0x4000 6000 - 0x4000 63FF	Reserved
	0x4000 5C00 - 0x4000 5FFF	12C3
	0x4000 5800 - 0x4000 5BFF	I2C2
	0x4000 5400 - 0x4000 57FF	I2C1
	0x4000 5000 - 0x4000 53FF	UART5
	0x4000 4C00 - 0x4000 4FFF	UART4
	0x4000 4800 - 0x4000 4BFF	USART3
	0x4000 4400 - 0x4000 47FF	USART2
	0x4000 4000 - 0x4000 43FF	I2S3ext
APB1	0x4000 3C00 - 0x4000 3FFF	SPI3 / I2S3
	0x4000 3800 - 0x4000 3BFF	SPI2 / I2S2
	0x4000 3400 - 0x4000 37FF	I2S2ext
	0x4000 3000 - 0x4000 33FF	IWDG
	0x4000 2C00 - 0x4000 2FFF	WWDG
	0x4000 2800 - 0x4000 2BFF	RTC & BKP Registers
	0x4000 2400 - 0x4000 27FF	Reserved
	0x4000 2000 - 0x4000 23FF	TIM14
	0x4000 1C00 - 0x4000 1FFF	TIM13
	0x4000 1800 - 0x4000 1BFF	TIM12
	0x4000 1400 - 0x4000 17FF	TIM7
	0x4000 1000 - 0x4000 13FF	TIM6
	0x4000 0C00 - 0x4000 0FFF	TIM5
	0x4000 0800 - 0x4000 0BFF	TIM4
	0x4000 0400 - 0x4000 07FF	TIM3
	0x4000 0000 - 0x4000 03FF	TIM2

 Table 10. STM32F41x register boundary addresses (continued)





Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	Regulator ON:	VOS bit in PWR_CR register = 0 ⁽¹⁾ Max frequency 144MHz	1.08	1.14	1.20	V
V ₁₂	V_{CAP_1}/V_{CAP_2} pins	VOS bit in PWR_CR register= 1 Max frequency 168MHz	1.20	1.26	1.32	V
12	Regulator OFF:	Max frequency 144MHz	1.10	1.14	1.20	V
	1.2 V external voltage must be supplied from external regulator on V_{CAP_1}/V_{CAP_2} pins	Max frequency 168MHz	1.20	1.26	1.30	V
	Input voltage on RST and FT	$2 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	-0.3	-	5.5	
	pins ⁽⁶⁾	$V_{DD} \le 2 V$	-0.3	-	5.2	
V _{IN}	Input voltage on TTa pins	-	-0.3	-	V _{DDA} + 0.3	V
	Input voltage on B pin	-	-	-	5.5	
		LQFP64	-	-	435	
		LQFP100	-	-	465	
Р	Power dissipation at $T_A = 85 \degree C$	LQFP144	-	-	500	m)//
PD	suffix $7^{(7)}$	LQFP176	-	-	526	mvv
		UFBGA176	-	-	513	
		WLCSP90	-	-	543	
	Ambient temperature for 6 suffix	Maximum power dissipation	-40	-	85	ŝ
т.	version	Low-power dissipation ⁽⁸⁾	-40	-	105	C
IA	Ambient temperature for 7 suffix	Maximum power dissipation	-40	-	105	ŝ
	version	Low-power dissipation ⁽⁸⁾	-40	-	125	C
т.	lunction tomporature range	6 suffix version	-40	-	105	°C
IJ	Sunction temperature range	7 suffix version	-40	-	125	U

Table 14. General	operating	conditions	(continued)	
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1. The average expected gain in power consumption when VOS = 0 compared to VOS = 1 is around 10% for the whole temperature range, when the system clock frequency is between 30 and 144 MHz.

 V_{DD}/V_{DDA} minimum value of 1.7 V is obtained when the device operates in reduced temperature range, and with the use of an external power supply supervisor (refer to Section : Internal reset OFF).

3. When the ADC is used, refer to *Table 67: ADC characteristics*.

4. If V_{REF+} pin is present, it must respect the following condition: V_{DDA}-V_{REF+} < 1.2 V.

5. It is recommended to power V_{DD} and V_{DDA} from the same source. A maximum difference of 300 mV between V_{DD} and V_{DDA} can be tolerated during power-up and power-down operation.

6. To sustain a voltage higher than V_{DD} +0.3, the internal pull-up and pull-down resistors must be disabled.

7. If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_{Jmax}

8. In low-power dissipation state, T_A can be extended to this range as long as T_J does not exceed T_{Jmax} .



Operating power supply range	ADC operation	Maximum Flash memory access frequency with no wait state (f _{Flashmax})	Maximum Flash memory access frequency with wait states ^{(1) (2)}	I/O operation	Clock output Frequency on I/O pins	Possible Flash memory operations
V _{DD} =1.8 to 2.1 V ⁽³⁾	Conversion time up to 1.2 Msps	20 MHz ⁽⁴⁾	160 MHz with 7 wait states	 Degraded speed performance No I/O compensation 	up to 30 MHz	8-bit erase and program operations only
V _{DD} = 2.1 to 2.4 V	Conversion time up to 1.2 Msps	22 MHz	168 MHz with 7 wait states	 Degraded speed performance No I/O compensation 	up to 30 MHz	16-bit erase and program operations
V _{DD} = 2.4 to 2.7 V	Conversion time up to 2.4 Msps	24 MHz	168 MHz with 6 wait states	 Degraded speed performance I/O compensation works 	up to 48 MHz	16-bit erase and program operations
V _{DD} = 2.7 to 3.6 V ⁽⁵⁾	Conversion time up to 2.4 Msps	30 MHz	168 MHz with 5 wait states	 Full-speed operation I/O compensation works 	- up to 60 MHz when VDD = 3.0 to 3.6 V - up to 48 MHz when VDD = 2.7 to 3.0 V	32-bit erase and program operations

 Table 15. Limitations depending on the operating power supply range

1. It applies only when code executed from Flash memory access, when code executed from RAM, no wait state is required.

2. Thanks to the ART accelerator and the 128-bit Flash memory, the number of wait states given here does not impact the execution speed from Flash memory since the ART accelerator allows to achieve a performance equivalent to 0 wait state program execution.

3. V_{DD}/VDDA minimum value of 1.7 V is obtained when the device operates in reduced temperature range, and with the use of an external power supply supervisor (refer to *Section : Internal reset OFF*).

4. Prefetch is not available. Refer to AN3430 application note for details on how to adjust performance and power.

5. The voltage range for OTG USB FS can drop down to 2.7 V. However it is degraded between 2.7 and 3 V.



0 4 0

20

40

60

80



Figure 26. Typical current consumption versus temperature, Run mode, code with data processing running from Flash (ART accelerator OFF) or RAM, and peripherals OFF

Figure 27. Typical current consumption versus temperature, Run mode, code with data processing running from Flash (ART accelerator OFF) or RAM, and peripherals ON

CPU Frequency (MHz

100

120

140

160

180

MS19976V1



		I _{DD} (T	yp) ⁽¹⁾	
Perip	heral	Scale1 (up t 168 MHz)	Scale2 (up to 144 MHz)	Unit
	SDIO	7.08	7.92	
	TIM1	16.79	15.51	
	TIM8	17.88	16.53	-
	TIM9	7.64	7.28	-
	TIM10	4.89	4.82	
	TIM11	5.19	4.82	
APB2 (up to 84 MHz)	ADC1 ⁽⁵⁾	4.67	4.58	µA/MHz
(up to 04 min2)	ADC2 ⁽⁵⁾	4.67	4.58	
	ADC3 ⁽⁵⁾	4.43	4.44	
	SPI1	1.32	1.39	
	USART1	3.51	3.72	
	USART6	3.55	3.75	1
	SYSCFG	0.74	0.56	1

 Table 28. Peripheral current consumption (continued)

1. When the I/O compensation cell is ON, I_{DD} typical value increases by 0.22 mA.

2. The BusMatrix is automatically active when at least one master is ON.

- 3. To enable an I2S peripheral, first set the I2SMOD bit and then the I2SE bit in the SPI_I2SCFGR register.
- 4. When the DAC is ON and EN1/2 bits are set in DAC_CR register, add an additional power consumption of 0.8 mA per DAC channel for the analog part.
- When the ADC is ON (ADON bit set in the ADC_CR2 register), add an additional power consumption of 1.6 mA per ADC for the analog part.

5.3.7 Wakeup time from low-power mode

The wakeup times given in *Table 29* is measured on a wakeup phase with a 16 MHz HSI RC oscillator. The clock source used to wake up the device depends from the current operating mode:

- Stop or Standby mode: the clock source is the RC oscillator
- Sleep mode: the clock source is the clock that was set before entering Sleep mode.

All timings are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 14*.





Figure 31. Low-speed external clock source AC timing diagram

High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 26 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 32*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f _{OSC_IN}	Oscillator frequency	-	4	-	26	MHz
R _F	Feedback resistor	-	-	200	-	kΩ
G _m	Oscillator transconductance	Startup	5	-	-	mAA/
G _{mcritmax}	Maximum critical crystal G _m	Startup	-	-	1	THAV V
t _{SU(HSE)} ⁽²⁾	Startup time	V_{DD} is stabilized	-	2	-	ms

Table 32. HSE 4-26 MHz oscillator characteristics ⁽¹	Table 32	. HSE 4-26	MHz oscillator	characteristics	(1)
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1. Guaranteed by design.

 Guaranteed by characterization. t_{SU(HSE)} is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and can vary significantly with the crystal manufacturer

For C_{L1} and C_{L2}, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 32*). C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2}. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2}.



Ethernet characteristics

Unless otherwise specified, the parameters given in *Table 64*, *Table 65* and *Table 66* for SMI, RMII and MII are derived from tests performed under the ambient temperature, f_{HCLK} frequency summarized in *Table 14* and VDD supply voltage conditions summarized in *Table 63*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C = 30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}.

Refer to Section 5.3.16: I/O port characteristics for more details on the input/output characteristics.

Symb	ol	Parameter	Min. ⁽¹⁾	Max. ⁽¹⁾	Unit
Input level	V _{DD}	Ethernet operating voltage	2.7	3.6	V

Table 63. Ethernet DC electrical characteristics

1. All the voltages are measured from the local ground potential.

Table 64 gives the list of Ethernet MAC signals for the SMI (station management interface) and *Figure 46* shows the corresponding timing diagram.



Figure 46. Ethernet SMI timing diagram

Table 64. Dynamic characteristics: Eternit	y MAC signals for SMI ⁽¹⁾
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Symbol	Parameter	Min	Тур	Мах	Unit
t _{MDC}	MDC cycle time(2.38 MHz)	411	420	425	
T _{d(MDIO)}	Write data valid time	6	10	13	ne
t _{su(MDIO)}	Read data setup time	12	-	-	115
t _{h(MDIO)}	Read data hold time	0	-	-	

1. Guaranteed by characterization.

Table 65 gives the list of Ethernet MAC signals for the RMII and *Figure 47* shows the corresponding timing diagram.



Symbol	Parameter	Min	Тур	Мах	Unit
t _{su(RXD)}	Receive data setup time	9		-	
t _{ih(RXD)}	Receive data hold time	10		-	
t _{su(DV)}	Data valid setup time	9		-	
t _{ih(DV)}	Data valid hold time	8		-	
t _{su(ER)}	Error setup time	6		-	115
t _{ih(ER)}	Error hold time	8		-	
t _{d(TXEN)}	Transmit enable valid delay time	0	10	14	
t _{d(TXD)}	Transmit data valid delay time	0	10	15	1

 Table 66. Dynamic characteristics: Ethernet MAC signals for MII⁽¹⁾

1. Guaranteed by characterization.

5.3.20 CAN (controller area network) interface

Refer to Section 5.3.16: I/O port characteristics for more details on the input/output alternate function characteristics (CANTX and CANRX).

5.3.21 12-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table* 67 are derived from tests performed under the ambient temperature, f_{PCLK2} frequency and V_{DDA} supply voltage conditions summarized in *Table* 14.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DDA}	Power supply	-	1.8 ⁽¹⁾	-	3.6	
V _{REF+}	Positive reference voltage	-	1.8 ⁽¹⁾⁽²⁾⁽³⁾	-	V _{DDA}	V
V_{REF-}	Negative reference voltage	-	-	0	-	
fADC ADC clock frequency		V _{DDA} = 1.8 ⁽¹⁾⁽³⁾ to 2.4 V	0.6	15	18	MHz
		V_{DDA} = 2.4 to 3.6 V ⁽³⁾	0.6	30	36	MHz
f _{TRIG} ⁽⁴⁾	External trigger frequency	f _{ADC} = 30 MHz, 12-bit resolution	-	-	1764	kHz
		-	-	-	17	1/f _{ADC}
V _{AIN}	Conversion voltage range ⁽⁵⁾	-	0 (V _{SSA} or V _{REF-} tied to ground)	-	V _{REF+}	V
R _{AIN} ⁽⁴⁾	External input impedance	See <i>Equation 1</i> for details	-	-	50	κΩ
R _{ADC} ⁽⁴⁾⁽⁶⁾	Sampling switch resistance	-	-	-	6	кΩ
C _{ADC} ⁽⁴⁾	Internal sample and hold capacitor	-	-	4	-	pF



Symbol	Parameter	Min	Тур	Мах	Unit	Comments
	Offset error		-	±10	mV	Given for the DAC in 12-bit configuration
Offset ⁽⁴⁾	(difference between measured value at Code (0x800) and the ideal value	-	-	±3	LSB	Given for the DAC in 10-bit at V _{REF+} = 3.6 V
	= V _{REF+} /2)	-	-	±12	LSB	Given for the DAC in 12-bit at V _{REF+} = 3.6 V
Gain error ⁽⁴⁾	Gain error	-	-	±0.5	%	Given for the DAC in 12-bit configuration
t _{SETTLING} ⁽⁴⁾	Settling time (full scale: for a 10-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches final value ±4LSB	-	3	6	μs	$C_{LOAD} \le 50 \text{ pF},$ $R_{LOAD} \ge 5 \text{ k}\Omega$
THD ⁽⁴⁾	Total Harmonic Distortion Buffer ON	-	-	-	dB	$\begin{array}{l} C_{LOAD} \leq 50 \text{ pF}, \\ R_{LOAD} \geq 5 k\Omega \end{array}$
Update rate ⁽²⁾	Max frequency for a correct DAC_OUT change when small variation in the input code (from code i to i+1LSB)	-	-	1	MS/s	$C_{LOAD} \le 50 \text{ pF},$ $R_{LOAD} \ge 5 \text{ k}\Omega$
t _{WAKEUP} ⁽⁴⁾	Wakeup time from off state (Setting the ENx bit in the DAC Control register)	-	6.5	10	μs	$\label{eq:loss} \begin{array}{l} C_{LOAD} \leq 50 \text{ pF}, \ R_{LOAD} \geq 5 \ k\Omega \\ \text{input code between lowest and} \\ \text{highest possible ones.} \end{array}$
PSRR+ ⁽²⁾	Power supply rejection ratio (to V_{DDA}) (static DC measurement)	-	-67	-40	dB	No R _{LOAD} , C _{LOAD} = 50 pF

Table 74.	DAC	characteristics	(continued)
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 V_{DD}/V_{DDA} minimum value of 1.7 V is obtained when the device operates in reduced temperature range, and with the use of an external power supply supervisor (refer to Section : Internal reset OFF).

2. Guaranteed by design.

3. The quiescent mode corresponds to a state where the DAC maintains a stable output level to ensure that no dynamic consumption occurs.

4. Guaranteed by characterization.



6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

6.1 WLCSP90 package information



Figure 75. WLCSP90 - 4.223 x 3.969 mm, 0.400 mm pitch wafer level chip scale package outline

1. Drawing is not to scale.

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Device marking for LFP100

The following figure gives an example of topside marking and pin 1 position identifier location.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.





 Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.







1. Dimensions are in millimeters.



Symbol		millimeters		inches ⁽¹⁾		
Symbol	Min	Тур	Мах	Min	Тур	Мах
ZD	-	1.250	-	-	0.0492	-
E	23.900	-	24.100	0.9409	-	0.9488
HE	25.900	-	26.100	1.0197	-	1.0276
ZE	-	1.250	-	-	0.0492	-
е	-	0.500	-	-	0.0197	-
L ⁽²⁾	0.450	-	0.750	0.0177	-	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	-	7°	0°	-	7°
ССС	-	-	0.080	-	-	0.0031

Table 97. LQFP176 - 176-pin, 24 x 24 mm low profile quad flat packagemechanical data (continued)

1. Values in inches are converted from mm and rounded to 4 decimal digits.

2. L dimension is measured at gauge plane at 0.25 mm above the seating plane.



Date	Revision	Changes		
Date	Revision	Changes Updated Figure 5: STM32F41xxx block diagram and Figure 7: Power supply supervisor interconnection with internal reset OFF Added SDIO, added notes related to FSMC and SPI/I2S in Table 2: STM32F415xx and STM32F417xx: features and peripheral counts. Starting from Silicon revision Z, USB OTG full-speed interface is now available for all STM32F415xx devices. Added full information on WLCSP90 package together with corresponding part numbers. Changed number of AHB buses to 3. Modified available Flash memory sizes in Section 2.2.4: Embedded Flash memory. Modified number of maskable interrupt channels in Section 2.2.10: Nested vectored interrupt controller (NVIC). Updated case of Regulator ON/internal reset ON, Regulator ON/internal reset OFF, and Regulator OFF/internal reset ON in Section 2.2.16: Voltage regulator. Updated standby mode description in Section 2.2.19: Low-power modes. Added Note 1 below Figure 16: STM32F41xxx UFBGA176 ballout. Added Table 7: STM32F41xxx pin and ball definitions. Added Table 7: STM32F41xxx pin and ball definitions. Added Table 8: FSMC pin definition. Removed OTG_HS_INTN alternate function in Table 7: STM32F41xxx pin and ball definitions and Table 9: Alternate function mapping. Replaced JTRST by NJTRST, removed ETH_RMII_TX_CLK, and modified I2S3ext_SD on PC11 in Table 9: Alternate function mapping. Added Table 10: STM32F41x		
		Typical and maximum current consumption in Sleep mode. Updated maximum current consumption at $T_A = 25$ °n Table 23: Typical and maximum current consumptions in Stop mode		

Table 100. Document revision history (continued)

